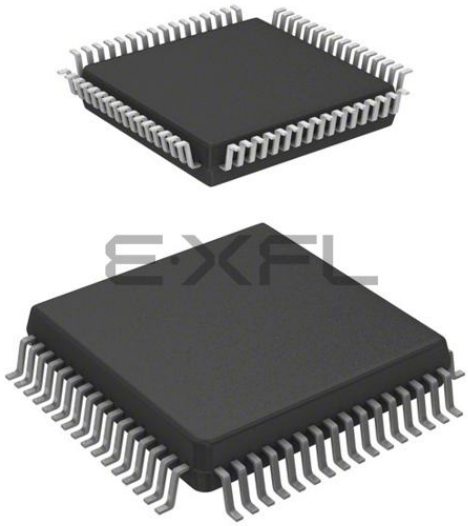

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Applications of "Embedded - Microcontrollers"

Details	
Product Status	Active
Core Processor	S08
Core Size	8-Bit
Speed	20MHz
Connectivity	I²C, LINbus, SPI, UART/USART
Peripherals	LVD, POR, PWM, WDT
Number of I/O	57
Program Memory Size	32KB (32K x 8)
Program Memory Type	FLASH
EEPROM Size	256 x 8
RAM Size	4K x 8
Voltage - Supply (Vcc/Vdd)	2.7V ~ 5.5V
Data Converters	A/D 16x12b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 105°C (TA)
Mounting Type	Surface Mount
Package / Case	64-QFP
Supplier Device Package	64-QFP (14x14)
Purchase URL	https://www.e-xfl.com/product-detail/nxp-semiconductors/mc9s08pa32avqh

- Input/Output
  - Up to 57 GPIOs including one output-only pin
  - Two 8-bit keyboard interrupt modules (KBI)
  - Two true open-drain output pins
  - Eight, ultra-high current sink pins supporting 20 mA source/sink current
- Package options
  - 64-pin LQFP; 64-pin QFP
  - 48-pin LQFP
  - 44-pin LQFP
  - 32-pin LQFP

Field	Description	Values
B	Operating temperature range (°C)	• V = –40 to 105
CC	Package designator	• QH = 64-pin QFP • LH = 64-pin LQFP • LF = 48-pin LQFP • LD = 44-pin LQFP • LC = 32-pin LQFP

2.4 Example

This is an example part number:

MC9S08PA60VQH

3 Parameter Classification

The electrical parameters shown in this supplement are guaranteed by various methods. To give the customer a better understanding, the following classification is used and the parameters are tagged accordingly in the tables where appropriate:

Table 1. Parameter Classifications

P	Those parameters are guaranteed during production testing on each individual device.
C	Those parameters are achieved by the design characterization by measuring a statistically relevant sample size across process variations.
T	Those parameters are achieved by design characterization on a small sample size from typical devices under typical conditions unless otherwise noted. All values shown in the typical column are within this category.
D	Those parameters are derived mainly from simulations.

NOTE

The classification is shown in the column labeled “C” in the parameter tables where appropriate.

4 Ratings

4.1 Thermal handling ratings

Symbol	Description	Min.	Max.	Unit	Notes
T_{STG}	Storage temperature	–55	150	°C	1
T_{SDR}	Solder temperature, lead-free	—	260	°C	2

1. Determined according to JEDEC Standard JESD22-A103, *High Temperature Storage Life*.
2. Determined according to IPC/JEDEC Standard J-STD-020, *Moisture/Reflow Sensitivity Classification for Nonhermetic Solid State Surface Mount Devices*.

4.2 Moisture handling ratings

Symbol	Description	Min.	Max.	Unit	Notes
MSL	Moisture sensitivity level	—	3	—	1

1. Determined according to IPC/JEDEC Standard J-STD-020, *Moisture/Reflow Sensitivity Classification for Nonhermetic Solid State Surface Mount Devices*.

4.3 ESD handling ratings

Symbol	Description	Min.	Max.	Unit	Notes
V_{HBM}	Electrostatic discharge voltage, human body model	-6000	+6000	V	1
V_{CDM}	Electrostatic discharge voltage, charged-device model	-500	+500	V	2
I_{LAT}	Latch-up current at ambient temperature of 105°C	-100	+100	mA	

1. Determined according to JEDEC Standard JESD22-A114, *Electrostatic Discharge (ESD) Sensitivity Testing Human Body Model (HBM)*.
2. Determined according to JEDEC Standard JESD22-C101, *Field-Induced Charged-Device Model Test Method for Electrostatic-Discharge-Withstand Thresholds of Microelectronic Components*.

4.4 Voltage and current operating ratings

Absolute maximum ratings are stress ratings only, and functional operation at the maxima is not guaranteed. Stress beyond the limits specified in below table may affect device reliability or cause permanent damage to the device. For functional operating conditions, refer to the remaining tables in this document.

Table 2. DC characteristics (continued)

Symbol	C	Descriptions			Min	Typical[1]	Max	Unit
I_{OHT}	D	Output high current	Max total I_{OH} for all ports	5 V	—	—	-100	mA
				3 V	—	—	-50	
V_{OL}	P	Output low voltage	All I/O pins, standard-drive strength	5 V, I_{load} = 5 mA	—	—	0.8	V
	C			3 V, I_{load} = 2.5 mA	—	—	0.8	V
	P		High current drive pins, high-drive strength[2]	5 V, I_{load} =20 mA	—	—	0.8	V
	C			3 V, I_{load} = 10 mA	—	—	0.8	V
I_{OLT}	D	Output low current	Max total I_{OL} for all ports	5 V	—	—	100	mA
				3 V	—	—	50	
V_{IH}	P	Input high voltage	All digital inputs	V_{DD}>4.5V	0.70 × V_{DD}	—	—	V
	C			V_{DD}>2.7V	0.75 × V_{DD}	—	—	
V_{IL}	P	Input low voltage	All digital inputs	V_{DD}>4.5V	—	—	0.30 × V_{DD}	V
	C			V_{DD}>2.7V	—	—	0.35 × V_{DD}	
V_{hys}	C	Input hysteresis	All digital inputs	—	0.06 × V_{DD}	—	—	mV
$\lvert I_{In}\rvert$	P	Input leakage current	All input only pins (per pin)	V_{IN} = V_{DD} or V_{SS}	—	0.1	1	µA
$\lvert I_{OZ}\rvert$	P	Hi-Z (off-state) leakage current	All input/output (per pin)	V_{IN} = V_{DD} or V_{SS}	—	0.1	1	µA
$\lvert I_{OZTOT}\rvert$	C	Total leakage combined for all inputs and Hi-Z pins	All input only and I/O	V_{IN} = V_{DD} or V_{SS}	—	—	2	µA
R_{PU}	P	Pullup resistors	All digital inputs, when enabled (all I/O pins other than PTA2 and PTA3)	—	30.0	—	50.0	kΩ
R_{PU}[3]	P	Pullup resistors	PTA2 and PTA3 pin	—	30.0	—	60.0	kΩ
I_{IC}	D	DC injection current[4, 5, 6]	Single pin limit	V_{IN} < V_{SS}, V_{IN} > V_{DD}	-0.2	—	2	mA
			Total MCU limit, includes sum of all stressed pins		-5	—	25	
C_{In}	C	Input capacitance, all pins		—	—	—	7	pF
V_{RAM}	C	RAM retention voltage		—	2.0	—	—	V

1. Typical values are measured at 25 °C. Characterized, not tested.
2. Only PTB4, PTB5, PTD0, PTD1, PTE0, PTE1, PTH0, and PTH1 support ultra high current output.
3. The specified resistor value is the actual value internal to the device. The pullup value may appear higher when measured externally on the pin.
4. All functional non-supply pins, except for PTA2 and PTA3, are internally clamped to V_{SS} and V_{DD}.
5. Input must be current-limited to the value specified. To determine the value of the required current-limiting resistor, calculate resistance values for positive and negative clamp voltages, then use the large one.

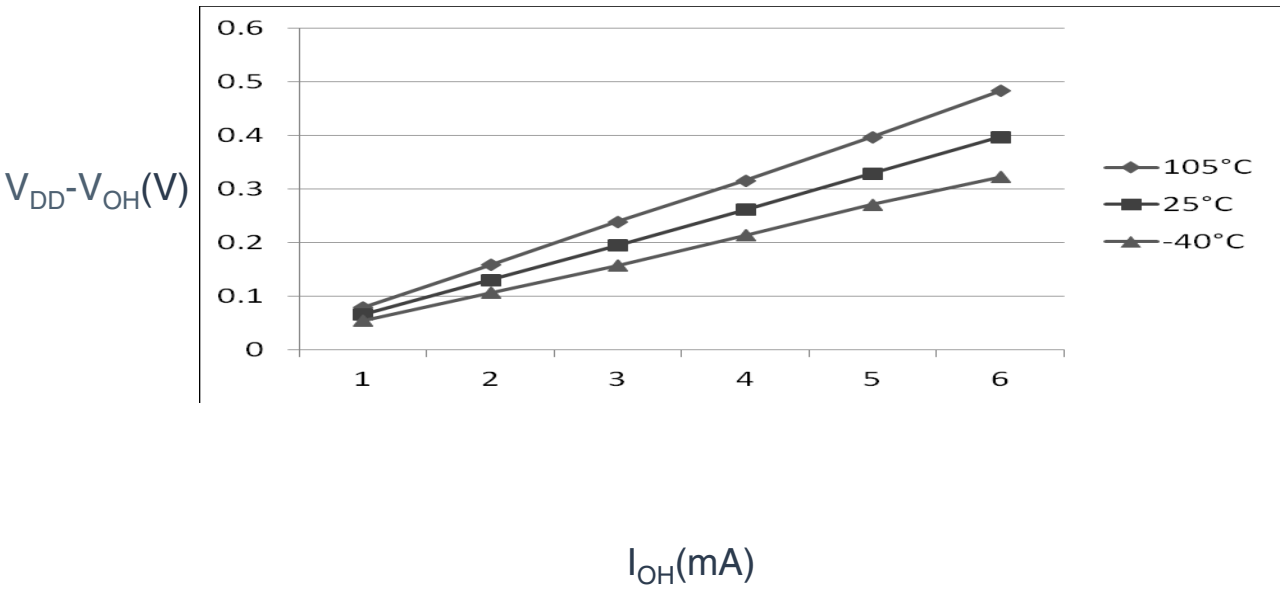


Figure 1. Typical I_{OH} Vs. V_{DD}-V_{OH} (standard drive strength) (V_{DD} = 5 V)

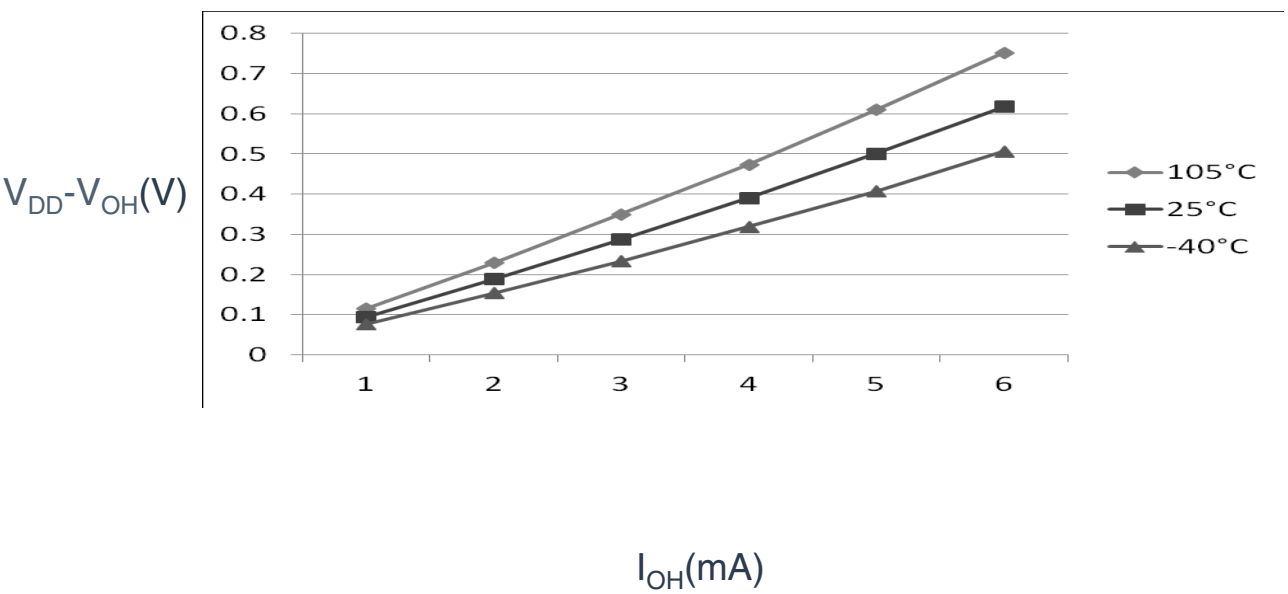


Figure 2. Typical I_{OH} Vs. V_{DD}-V_{OH} (standard drive strength) (V_{DD} = 3 V)

5.1.2 Supply current characteristics

This section includes information about power supply current in various operating modes.

Table 4. Supply current characteristics

Num	C	Parameter	Symbol	Bus Freq	V_{DD} (V)	Typical[1]	Max	Unit	Temp
1	C	Run supply current FEI mode, all modules on; run from flash	RI_{DD}	20 MHz	5	12.6	—	mA	-40 to 105 °C
	C			10 MHz		7.2	—		
				1 MHz		2.4	—		
	C			20 MHz	3	9.6	—		
	C			10 MHz		6.1	—		
				1 MHz		2.1	—		
2	C	Run supply current FEI mode, all modules off & gated; run from flash	RI_{DD}	20 MHz	5	10.5	—	mA	-40 to 105 °C
	C			10 MHz		6.2	—		
				1 MHz		2.3	—		
	C			20 MHz	3	7.4	—		
	C			10 MHz		5.0	—		
				1 MHz		2.0	—		
3	P	Run supply current FBE mode, all modules on; run from RAM	RI_{DD}	20 MHz	5	12.1	14.8	mA	-40 to 105 °C
	C			10 MHz		6.5	—		
				1 MHz		1.8	—		
	P			20 MHz	3	9.1	11.8		
	C			10 MHz		5.5	—		
				1 MHz		1.5	—		
4	P	Run supply current FBE mode, all modules off & gated; run from RAM	RI_{DD}	20 MHz	5	9.8	12.3	mA	-40 to 105 °C
	C			10 MHz		5.4	—		
				1 MHz		1.6	—		
	P			20 MHz	3	6.9	9.2		
	C			10 MHz		4.4	—		
				1 MHz		1.4	—		
5	C	Wait mode current FEI mode, all modules on	WI_{DD}	20 MHz	5	7.8	—	mA	-40 to 105 °C
	C			10 MHz		4.5	—		
				1 MHz		1.3	—		
	C			20 MHz	3	5.1	—		
				10 MHz		3.5	—		
				1 MHz		1.2	—		
6	C	Stop3 mode supply current no clocks active (except 1 kHz LPO clock)[2, 3]	$S3I_{DD}$	—	5	3.8	—	µA	-40 to 105 °C
	C			—	3	3	—		-40 to 105 °C
7	C	ADC adder to stop3	—	—	5	44	—	µA	-40 to 105 °C

Table continues on the next page...

5.2 Switching specifications

5.2.1 Control timing

Table 6. Control timing

Num	C	Rating		Symbol	Min	Typical[1]	Max	Unit
1	P	Bus frequency ($t_{cyc} = 1/f_{Bus}$)		f_{Bus}	DC	—	20	MHz
2	P	Internal low power oscillator frequency		f_{LPO}	0.67	1.0	1.25	KHz
3	D	External reset pulse width[2]		t_{extrst}	1.5 × t_{cyc}	—	—	ns
4	D	Reset low drive		t_{rstdrv}	34 × t_{cyc}	—	—	ns
5	D	BKGD/MS setup time after issuing background debug force reset to enter user or BDM modes		t_{MSSU}	500	—	—	ns
6	D	BKGD/MS hold time after issuing background debug force reset to enter user or BDM modes[3]		t_{MSH}	100	—	—	ns
7	D	IRQ pulse width	Asynchronous path[2]	t_{ILIH}	100	—	—	ns
	D		Synchronous path[4]	t_{IHIL}	1.5 × t_{cyc}	—	—	ns
8	D	Keyboard interrupt pulse width	Asynchronous path[2]	t_{ILIH}	100	—	—	ns
	D		Synchronous path	t_{IHIL}	1.5 × t_{cyc}	—	—	ns
9	C	Port rise and fall time - standard drive strength (load = 50 pF)[5]	—	t_{Rise}	—	10.2	—	ns
	C			t_{Fall}	—	9.5	—	ns
	C	Port rise and fall time - high drive strength (load = 50 pF)[5]	—	t_{Rise}	—	5.4	—	ns
	C			t_{Fall}	—	4.6	—	ns

1. Typical values are based on characterization data at V_{DD} = 5.0 V, 25 °C unless otherwise stated.
2. This is the shortest pulse that is guaranteed to be recognized as a reset pin request.
3. To enter BDM mode following a POR, BKGD/MS must be held low during the powerup and for a hold time of t_{MSH} after V_{DD} rises above V_{LVD}.
4. This is the minimum pulse width that is guaranteed to pass through the pin synchronization circuitry. Shorter pulses may or may not be recognized. In stop mode, the synchronizer is bypassed so shorter pulses can be recognized.
5. Timing is shown with respect to 20% V_{DD} and 80% V_{DD} levels in operating temperature range.

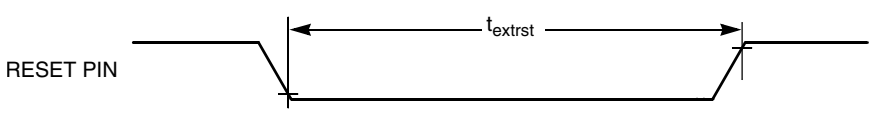


Figure 9. Reset timing

5.2.3 FTM module timing

Synchronizer circuits determine the shortest input pulses that can be recognized or the fastest clock that can be used as the optional external source to the timer counter. These synchronizers operate from the current bus rate clock.

Table 8. FTM input timing

No.	C	Function	Symbol	Min	Max	Unit
1	D	External clock frequency	f_{TCLK}	0	$f_{Bus}/4$	Hz
2	D	External clock period	t_{TCLK}	4	—	t_{cyc}
3	D	External clock high time	t_{clkh}	1.5	—	t_{cyc}
4	D	External clock low time	t_{clkl}	1.5	—	t_{cyc}
5	D	Input capture pulse width	t_{ICPW}	1.5	—	t_{cyc}

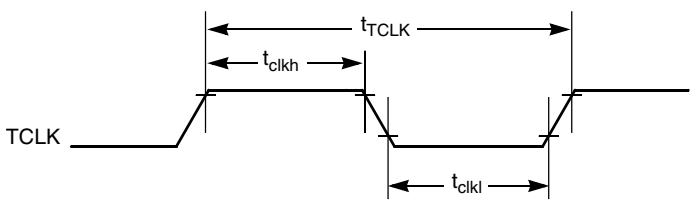


Figure 13. Timer external clock

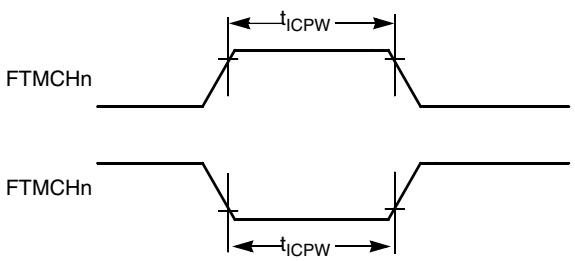


Figure 14. Timer input capture pulse

5.3 Thermal specifications

5.3.1 Thermal operating requirements

Table 9. Thermal operating requirements

Symbol	Description	Min.	Max.	Unit
T_J	Die junction temperature	–40	125	°C
T_A	Ambient temperature	–40	105	°C

NOTE

Maximum T_A can be exceeded only if the user ensures that T_J does not exceed the maximum. The simplest method to determine T_J is: $T_J = T_A + R_{\theta JA} \times$ chip power dissipation.

5.3.2 Thermal characteristics

This section provides information about operating temperature range, power dissipation, and package thermal resistance. Power dissipation on I/O pins is usually small compared to the power dissipation in on-chip logic and voltage regulator circuits, and it is user-determined rather than being controlled by the MCU design. To take $P_{I/O}$ into account in power calculations, determine the difference between actual pin voltage and V_{SS} or V_{DD} and multiply by the pin current for each I/O pin. Except in cases of unusually high pin current (heavy loads), the difference between pin voltage and V_{SS} or V_{DD} will be very small.

Table 10. Thermal attributes

Board type	Symbol	Description	64 LQFP	64 QFP	48 LQFP	44 LQFP	32 LQFP	Unit	Notes
Single-layer (1S)	$R_{\theta JA}$	Thermal resistance, junction to ambient (natural convection)	71	61	81	75	86	°C/W	1, 2
Four-layer (2s2p)	$R_{\theta JA}$	Thermal resistance, junction to ambient (natural convection)	53	47	57	53	57	°C/W	1, 3
Single-layer (1S)	$R_{\theta JMA}$	Thermal resistance, junction to ambient (200 ft./ min. air speed)	59	50	68	62	72	°C/W	1, 3
Four-layer (2s2p)	$R_{\theta JMA}$	Thermal resistance, junction to ambient (200 ft./ min. air speed)	46	41	50	47	51	°C/W	1, 3

Table continues on the next page...

Table 10. Thermal attributes (continued)

Board type	Symbol	Description	64 LQFP	64 QFP	48 LQFP	44 LQFP	32 LQFP	Unit	Notes
—	$R_{\theta JB}$	Thermal resistance, junction to board	35	32	34	34	33	°C/W	4
—	$R_{\theta JC}$	Thermal resistance, junction to case	20	23	24	20	24	°C/W	5
—	Ψ_{JT}	Thermal characterization parameter, junction to package top outside center (natural convection)	5	8	6	5	6	°C/W	6

1. Junction temperature is a function of die size, on-chip power dissipation, package thermal resistance, mounting site (board) temperature, ambient temperature, air flow, power dissipation of other components on the board, and board thermal resistance.
2. Per JEDEC JESD51-2 with the single layer board (JESD51-3) horizontal.
3. Per JEDEC JESD51-6 with the board (JESD51-7) horizontal.
4. Thermal resistance between the die and the printed circuit board per JEDEC JESD51-8. Board temperature is measured on the top surface of the board near the package.
5. Thermal resistance between the die and the solder pad on the bottom of the package. Interface resistance is ignored.
6. Thermal characterization parameter indicating the temperature difference between package top and the junction temperature per JEDEC JESD51-2. When Greek letters are not available, the thermal characterization.

6 Peripheral operating requirements and behaviors

6.1 External oscillator (XOSC) and ICS characteristics

Table 11. XOSC and ICS specifications (temperature range = -40 to 105 °C ambient)

Num	C	Characteristic		Symbol	Min	Typical[1]	Max	Unit
1	C	Oscillator crystal or resonator	Low range (RANGE = 0)	f_{lo}	31.25	32.768	39.0625	kHz
	C		High range (RANGE = 1) FEE or FBE mode[2]	f_{hi}	4	—	20	MHz
	C		High range (RANGE = 1), high gain (HGO = 1), FBELP mode	f_{hi}	4	—	20	MHz
	C		High range (RANGE = 1), low power (HGO = 0), FBELP mode	f_{hi}	4	—	20	MHz
2	D	Load capacitors		C1, C2	See Note[3]			
3	D	Feedback resistor	Low Frequency, Low-Power Mode[4]	R_F	—	—	—	MΩ
			Low Frequency, High-Gain Mode		—	10	—	MΩ
			High Frequency, Low-Power Mode		—	1	—	MΩ

Table continues on the next page...

Table 11. XOSC and ICS specifications (temperature range = -40 to 105 °C ambient) (continued)

Num	C	Characteristic		Symbol	Min	Typical[1]	Max	Unit
			High Frequency, High-Gain Mode		—	1	—	MΩ
4	D	Series resistor - Low Frequency	Low-Power Mode [4]	R_S	—	—	—	kΩ
			High-Gain Mode		—	200	—	kΩ
5	D	Series resistor - High Frequency	Low-Power Mode[4]	R_S	—	—	—	kΩ
	D	Series resistor - High Frequency, High-Gain Mode	4 MHz		—	0	—	kΩ
	D		8 MHz		—	0	—	kΩ
	D		16 MHz		—	0	—	kΩ
6	C	Crystal start-up time Low range = 32.768 kHz crystal; High range = 20 MHz crystal[5, 6]	Low range, low power	t_{CSTL}	—	1000	—	ms
	C		Low range, high power		—	800	—	ms
	C		High range, low power	t_{CSTH}	—	3	—	ms
	C		High range, high power		—	1.5	—	ms
7	T	Internal reference start-up time		t_{IRST}	—	20	50	µs
8	D	Square wave input clock frequency	FEE or FBE mode[2]	f_{extal}	0.03125	—	5	MHz
	D		FBELP mode		0	—	20	MHz
9	P	Average internal reference frequency - trimmed		f_{int_t}	—	32.768	—	kHz
10	P	DCO output frequency range - trimmed		f_{dco_t}	16	—	20	MHz
11	P	Total deviation of DCO output from trimmed frequency[5]	Over full voltage and temperature range	Δf_{dco_t}	—	—	±2.0	$\%f_{dco}$
	C		Over fixed voltage and temperature range of 0 to 70 °C				±1.0	
12	C	FLL acquisition time[5, 7]		$t_{Acquire}$	—	—	2	ms
13	C	Long term jitter of DCO output clock (averaged over 2 ms interval)[8]		C_{Jitter}	—	0.02	0.2	$\%f_{dco}$

1. Data in Typical column was characterized at 5.0 V, 25 °C or is typical recommended value.
2. When ICS is configured for FEE or FBE mode, input clock source must be divisible using RDIV to within the range of 31.25 kHz to 39.0625 kHz.
3. See crystal or resonator manufacturer's recommendation.
4. Load capacitors (C_1,C_2), feedback resistor (R_F) and series resistor (R_S) are incorporated internally when RANGE = HGO = 0.
5. This parameter is characterized and not tested on each device.
6. Proper PC board layout procedures must be followed to achieve specifications.
7. This specification applies to any time the FLL reference source or reference divider is changed, trim value changed, or changing from FLL disabled (FBELP, FBILP) to FLL enabled (FEI, FEE, FBE, FBI). If a crystal/resonator is being used as the reference, this specification assumes it is already running.
8. Jitter is the average deviation from the programmed frequency measured over the specified interval at maximum f_{Bus}. Measurements are made with the device powered by filtered supplies and clocked by a stable external clock signal. Noise injected into the FLL circuitry via V_{DD} and V_{SS} and variation in crystal oscillator frequency increase the C_{Jitter} percentage for a given interval.

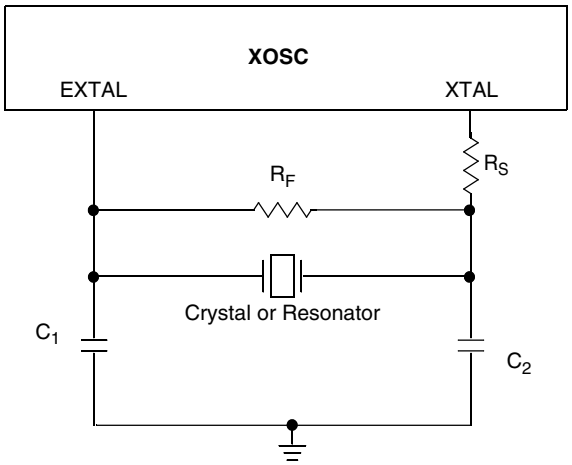


Figure 15. Typical crystal or resonator circuit

6.2 NVM specifications

This section provides details about program/erase times and program/erase endurance for the flash and EEPROM memories.

Table 12. Flash characteristics

C	Characteristic	Symbol	Min[1]	Typical[2]	Max[3]	Unit[4]
D	Supply voltage for program/erase -40 °C to 105 °C	$V_{prog/erase}$	2.7	—	5.5	V
D	Supply voltage for read operation	V_{Read}	2.7	—	5.5	V
D	NVM Bus frequency	f_{NVMBUS}	1	—	25	MHz
D	NVM Operating frequency	f_{NVMOP}	0.8	1	1.05	MHz
D	Erase Verify All Blocks	t_{VFYALL}	—	—	17338	t_{cyc}
D	Erase Verify Flash Block	t_{RD1BLK}	—	—	16913	t_{cyc}
D	Erase Verify EEPROM Block	t_{RD1BLK}	—	—	810	t_{cyc}
D	Erase Verify Flash Section	t_{RD1SEC}	—	—	484	t_{cyc}
D	Erase Verify EEPROM Section	$t_{DRD1SEC}$	—	—	555	t_{cyc}
D	Read Once	t_{RDONCE}	—	—	450	t_{cyc}
D	Program Flash (2 word)	t_{PGM2}	0.12	0.12	0.29	ms
D	Program Flash (4 word)	t_{PGM4}	0.20	0.21	0.46	ms
D	Program Once	$t_{PGMONCE}$	0.20	0.21	0.21	ms
D	Program EEPROM (1 Byte)	t_{DPGM1}	0.10	0.10	0.27	ms
D	Program EEPROM (2 Byte)	t_{DPGM2}	0.17	0.18	0.43	ms
D	Program EEPROM (3 Byte)	t_{DPGM3}	0.25	0.26	0.60	ms
D	Program EEPROM (4 Byte)	t_{DPGM4}	0.32	0.33	0.77	ms
D	Erase All Blocks	t_{ERSALL}	96.01	100.78	101.49	ms
D	Erase Flash Block	t_{ERSBLK}	95.98	100.75	101.44	ms

Table continues on the next page...

Table 14. 12-bit ADC Characteristics ($V_{REFH} = V_{DDA}$, $V_{REFL} = V_{SSA}$) (continued)

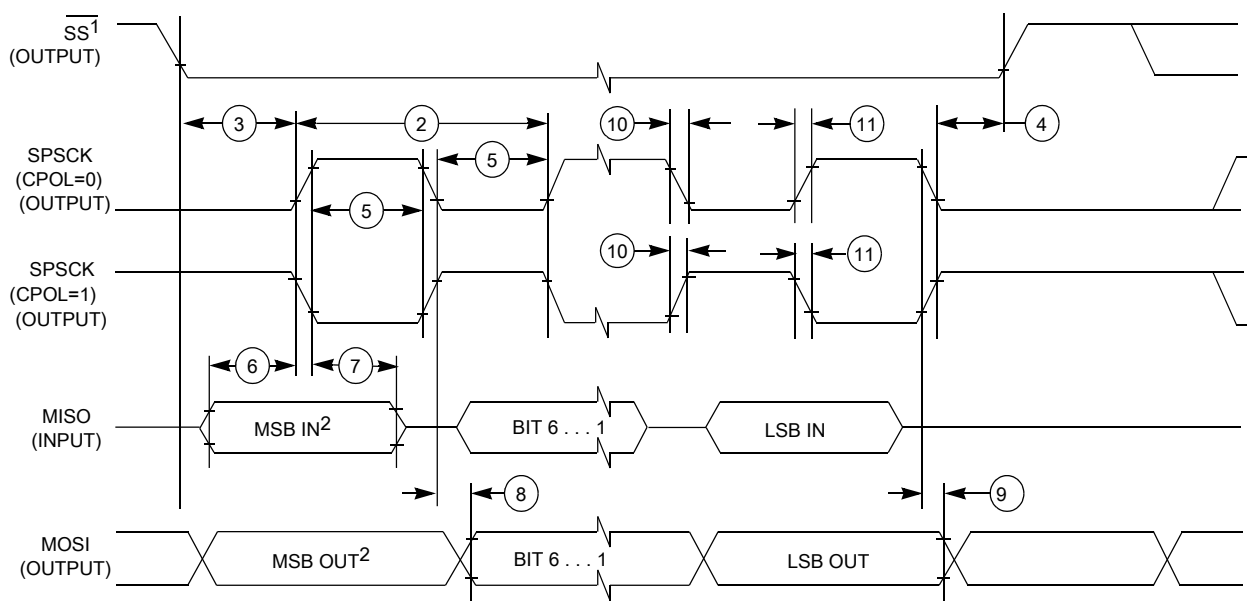
Characteristic	Conditions	C	Symb	Min	Typ[1]	Max	Unit
ADLPC = 1 ADLSMP = 0 ADCO = 1							
Supply current ADLPC = 0 ADLSMP = 1 ADCO = 1		T	I_{DDA}	—	327	—	µA
Supply current ADLPC = 0 ADLSMP = 0 ADCO = 1		T	I_{DDAD}	—	582	990	µA
Supply current	Stop, reset, module off	T	I_{DDA}	—	0.011	1	µA
ADC asynchronous clock source	High speed (ADLPC = 0)	P	f_{ADACK}	2	3.3	5	MHz
	Low power (ADLPC = 1)			1.25	2	3.3	
Conversion time (including sample time)	Short sample (ADLSMP = 0)	T	t_{ADC}	—	20	—	ADCK cycles
	Long sample (ADLSMP = 1)			—	40	—	
Sample time	Short sample (ADLSMP = 0)	T	t_{ADS}	—	3.5	—	ADCK cycles
	Long sample (ADLSMP = 1)			—	23.5	—	
Total unadjusted Error[2]	12-bit mode	T	E_{TUE}	—	±5.0	—	LSB[3]
	10-bit mode	P		—	±1.5	±2.0	
	8-bit mode	P		—	±0.7	±1.0	
Differential Non-Linearity	12-bit mode	T	DNL	—	±1.0	—	LSB[3]
	10-bit mode[4]	P		—	±0.25	±0.5	
	8-bit mode[4]	P		—	±0.15	±0.25	
Integral Non-Linearity	12-bit mode	T	INL	—	±1.0	—	LSB[3]
	10-bit mode	T		—	±0.3	±0.5	
	8-bit mode	T		—	±0.15	±0.25	
Zero-scale error[5]	12-bit mode	C	E_{ZS}	—	±2.0	—	LSB[3]
	10-bit mode	P		—	±0.25	±1.0	
	8-bit mode	P		—	±0.65	±1.0	
Full-scale error[6]	12-bit mode	T	E_{FS}	—	±2.5	—	LSB[3]
	10-bit mode	T		—	±0.5	±1.0	
	8-bit mode	T		—	±0.5	±1.0	
Quantization error	≤12 bit modes	D	E_Q	—	—	±0.5	LSB[3]

Table continues on the next page...

communicating with slower peripheral devices. All timing is shown with respect to 20% V_{DD} and 70% V_{DD}, unless noted, and 100 pF load on all SPI pins. All timing assumes high drive strength is enabled for SPI output pins.

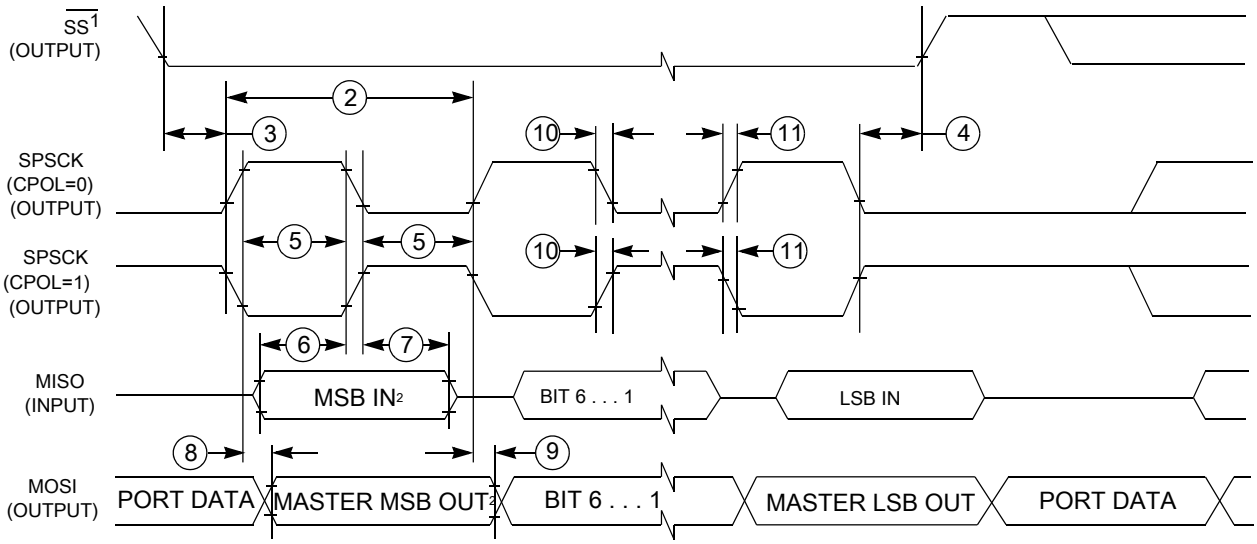
Table 16. SPI master mode timing

Num.	Symbol	Description	Min.	Max.	Unit	Comment
1	f_{op}	Frequency of operation	$f_{Bus}/2048$	$f_{Bus}/2$	Hz	f_{Bus} is the bus clock
2	t_{SPSCK}	SPSCK period	2 x t_{Bus}	2048 x t_{Bus}	ns	$t_{Bus} = 1/f_{Bus}$
3	t_{Lead}	Enable lead time	1/2	—	t_{SPSCK}	—
4	t_{Lag}	Enable lag time	1/2	—	t_{SPSCK}	—
5	t_{WSPSCK}	Clock (SPSCK) high or low time	t_{Bus} - 30	1024 x t_{Bus}	ns	—
6	t_{SU}	Data setup time (inputs)	15	—	ns	—
7	t_{HI}	Data hold time (inputs)	0	—	ns	—
8	t_{v}	Data valid (after SPSCK edge)	—	25	ns	—
9	t_{HO}	Data hold time (outputs)	0	—	ns	—
10	t_{RI}	Rise time input	—	t_{Bus} - 25	ns	—
	t_{FI}	Fall time input				
11	t_{RO}	Rise time output	—	25	ns	—
	t_{FO}	Fall time output				



1. If configured as an output.
2. LSBF = 0. For LSBF = 1, bit order is LSB, bit 1, ..., bit 6, MSB.

Figure 17. SPI master mode timing (CPHA=0)



1.If configured as output

2. LSBF = 0. For LSBF = 1, bit order is LSB, bit 1, ..., bit 6, MSB.

Figure 18. SPI master mode timing (CPHA=1)

Table 17. SPI slave mode timing

Num.	Symbol	Description	Min.	Max.	Unit	Comment
1	f_{op}	Frequency of operation	0	$f_{Bus}/4$	Hz	f_{Bus} is the bus clock as defined in .
2	t_{SPSCK}	SPSCK period	4 x t_{Bus}	—	ns	$t_{Bus} = 1/f_{Bus}$
3	t_{Lead}	Enable lead time	1	—	t_{Bus}	—
4	t_{Lag}	Enable lag time	1	—	t_{Bus}	—
5	t_{WSPSCK}	Clock (SPSCK) high or low time	t_{Bus} - 30	—	ns	—
6	t_{SU}	Data setup time (inputs)	15	—	ns	—
7	t_{HI}	Data hold time (inputs)	25	—	ns	—
8	t_a	Slave access time	—	t_{Bus}	ns	Time to data active from high-impedance state
9	t_{dis}	Slave MISO disable time	—	t_{Bus}	ns	Hold time to high-impedance state
10	t_v	Data valid (after SPSCK edge)	—	25	ns	—
11	t_{HO}	Data hold time (outputs)	0	—	ns	—
12	t_{RI}	Rise time input	—	t_{Bus} - 25	ns	—
	t_{FI}	Fall time input				
13	t_{RO}	Rise time output	—	25	ns	—
	t_{FO}	Fall time output				

Table 18. Pin availability by package pin-count (continued)

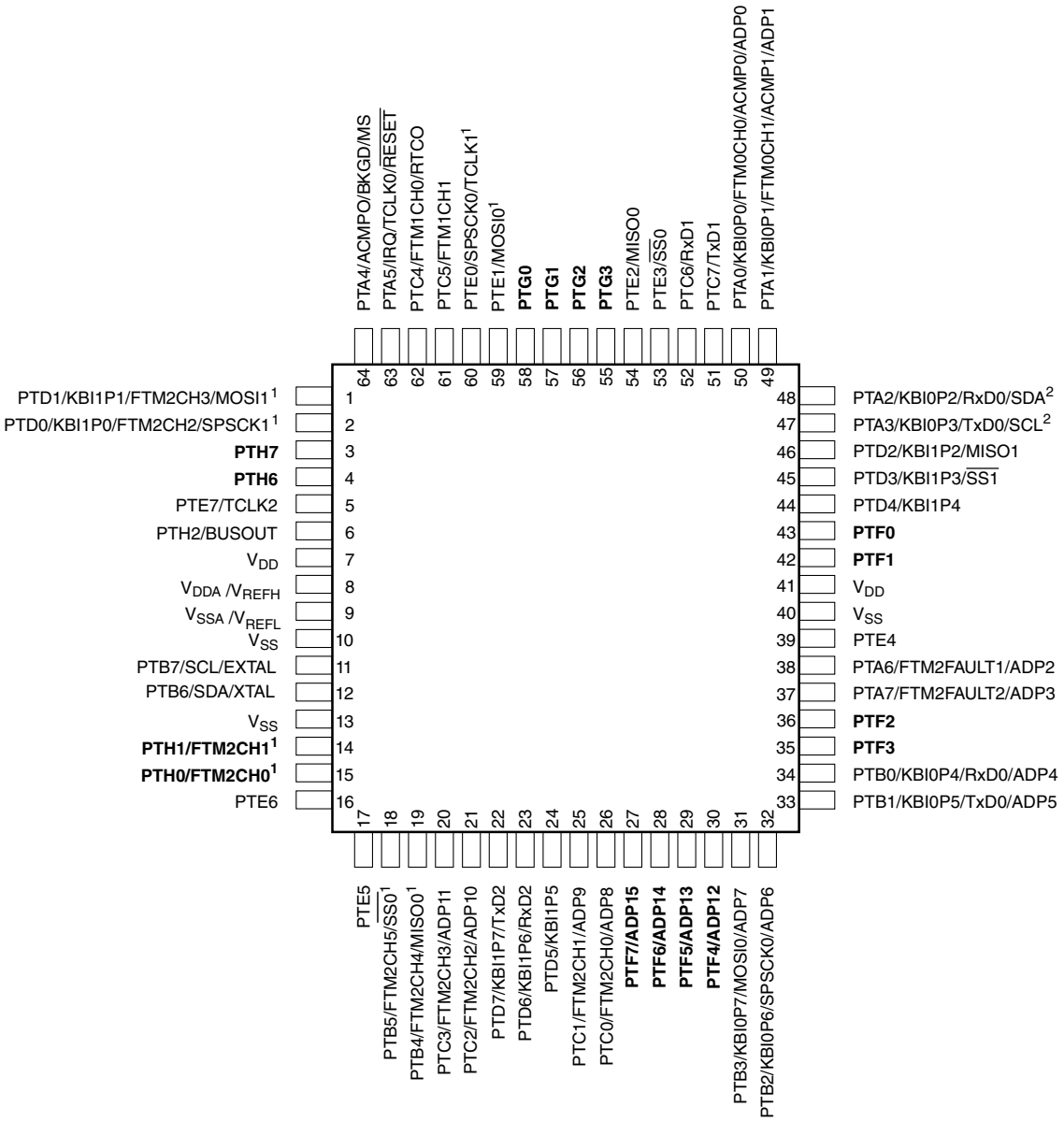
Pin Number				Lowest Priority <-- --> Highest				
64-LQFP 64-QFP	48-LQFP	44-LQFP	32-LQFP	Port Pin	Alt 1	Alt 2	Alt 3	Alt 4
54	42	38	—	PTE2	—	MISO0	—	—
55	—	—	—	PTG3	—	—	—	—
56	—	—	—	PTG2	—	—	—	—
57	—	—	—	PTG1	—	—	—	—
58	—	—	—	PTG0	—	—	—	—
59	43	39	—	PTE1[1]	—	MOSI0	—	—
60	44	40	—	PTE0[1]	—	SPSCK0	TCLK1	—
61	45	41	29	PTC5	—	FTM1CH1	—	—
62	46	42	30	PTC4	—	FTM1CH0	RTCO	—
63	47	43	31	PTA5	IRQ	TCLK0	—	$\overline{\text{RESET}}$
64	48	44	32	PTA4	—	ACMPO	BKGD	MS

1. This is a high current drive pin when operated as output.
2. This is a true open-drain pin when operated as output.

Note

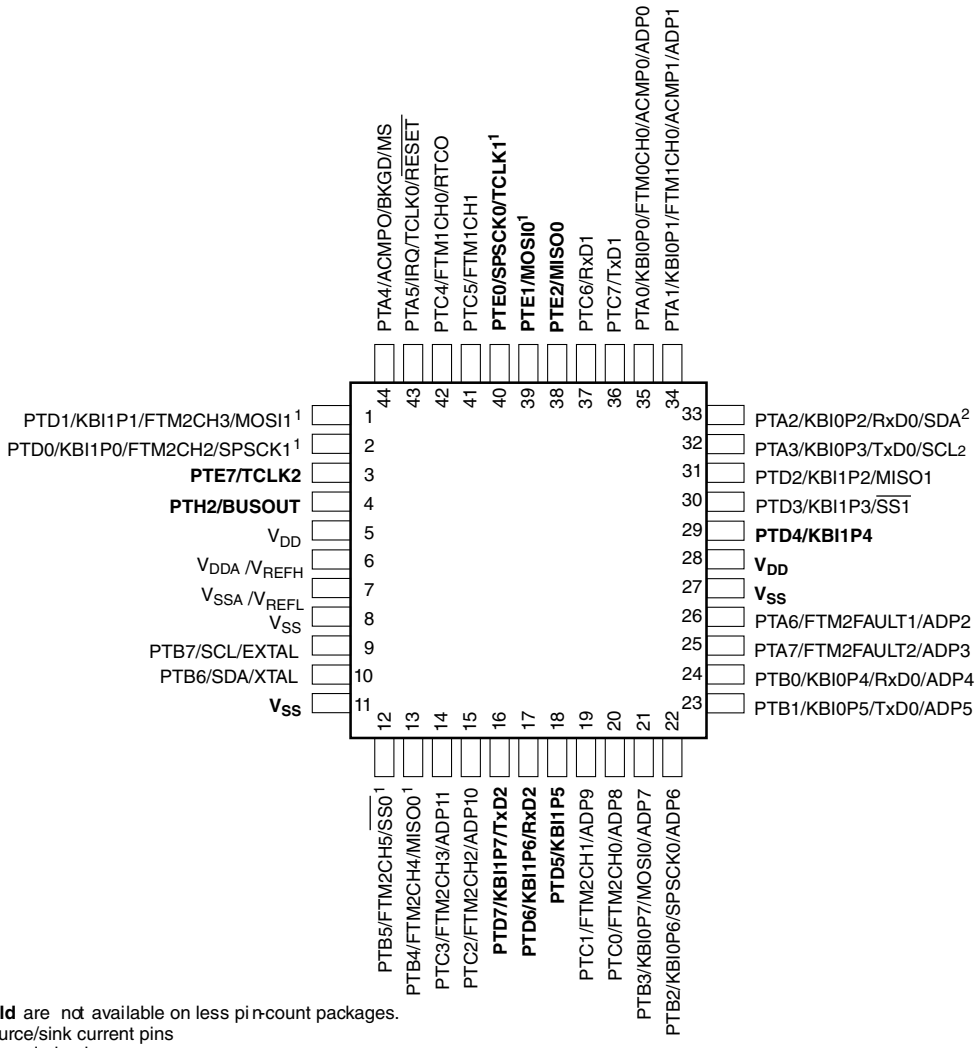
When an alternative function is first enabled, it is possible to get a spurious edge to the module. User software must clear any associated flags before interrupts are enabled. The table above illustrates the priority if multiple modules are enabled. The highest priority module will have control over the pin. Selecting a higher priority pin function with a lower priority function already enabled can cause spurious edges to the lower priority module. Disable all modules that share a pin before enabling another module.

8.2 Device pin assignment



Pins in **bold** are not available on less pin-count packages.
1. High source/sink current pins
2. True open drain pins

Figure 21. MC9S08PA60 64-pin QFP and LQFP package



Pins in **bold** are not available on less pin-count packages.
1. High source/sink current pins
2. True open drain pins

Figure 23. MC9S08PA60 44-pin LQFP package

Table 19. Revision history (continued)

Rev. No.	Date	Substantial Changes
		• Updated the rating descriptions for t_{Rise} and t_{Fall} in Control timing • Updated the part number format to add new field for new part numbers in Fields
3	06/2015	• Corrected the Min. of the t_{extrst} in Control timing • Added new section of Thermal operating requirements, Updated Thermal characteristics to remove redundant information.

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